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	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/665,849	KRIS ET AL.
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	Yuzhen Ge	2624

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SEARCH NOT (INCLUDING SEARCH)
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EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout	12/5/2006	YG
IEEE Xplore - See search session history printout	12/5/2006	YG
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